

IC Validator

2X Faster with 1/2 Resources

Vikas Gupta
Senior Director, Asia Pacific
August 2024

CONFIDENTIAL INFORMATION



The information contained in this presentation is the confidential and proprietary information of Synopsys. You are not permitted to disseminate or use any of the information provided to you in this presentation outside of Synopsys without prior written authorization.

IMPORTANT NOTICE

In the event information in this presentation reflects Synopsys' future plans, such plans are as of the date of this presentation and are subject to change. Synopsys is not obligated to update this presentation or develop the products with the features and functionality discussed in this presentation. Additionally, Synopsys' services and products may only be offered and purchased pursuant to an authorized quote and purchase order or a mutually agreed upon written contract with Synopsys.

Agenda

- Challenges at advanced nodes
- Why IC Validator
- Customer case studies
- Technology differentiators
- ESD solution
- License package

Challenge



DECIDING WHERE TO EAT



LONG CAI FAN QUEUES



DISAPPEARING FOOD



BOJIO BUBBLE TEA

Solution

Where to Eat?



Long Cai Fan Queues

MAXIMISE YOUR CAI PNG ORDER



ORDER MOST EXPENSIVE DISH FIRST

Seafood or Fish > Meat
> Veggies

LINGER WHEN CHOOSING

Keep pointing and you
might get more

ASK FOR "A LITTLE MORE RICE"

Not "Add Rice"

CHOOSE DISHES CLOSE TO EACH OTHER

Make it easier for the
person scooping

LOOK FOR DISHES THAT'RE RUNNING OUT

Might get everything +
something extra!

ORDER LESS QUANTIFIABLE DISHES

Sweet & Sour Pork vs
a whole Pork Cutlet

or get the economic rice auntie to like you...

Disappearing Food

SYNOPSIS[®]



Sharing Bubble Tea??

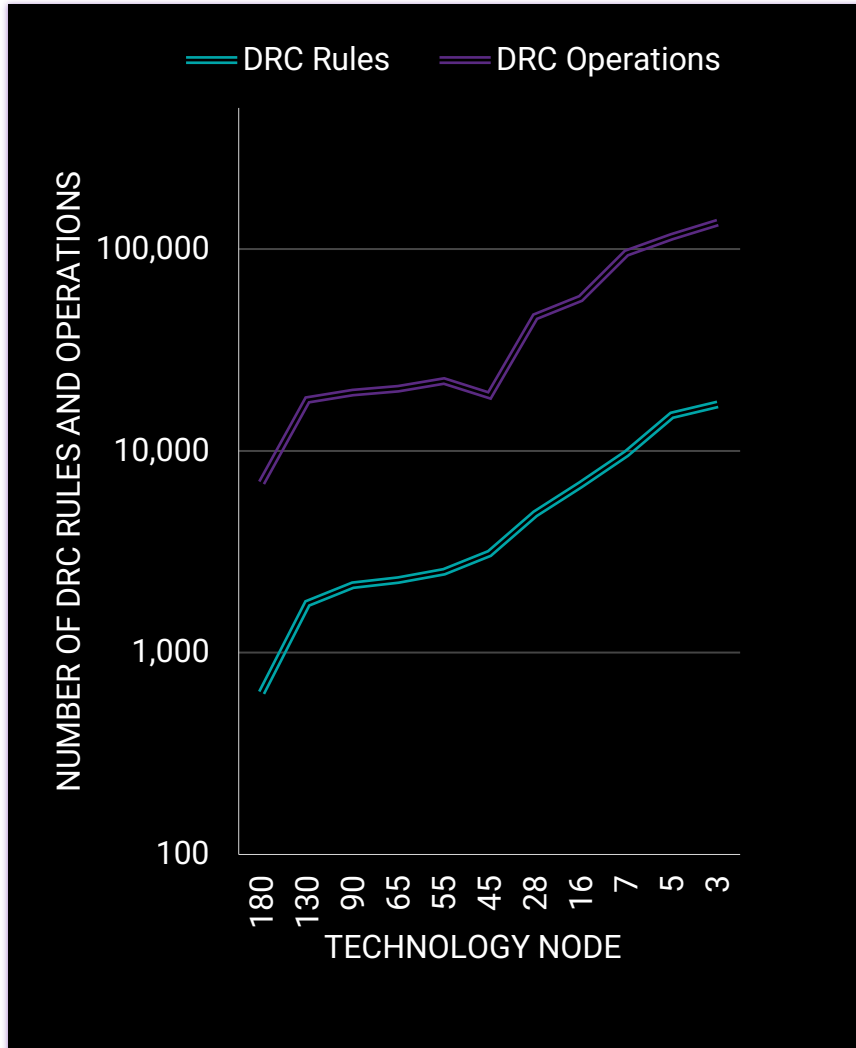
Just a heads up that
I'm drinking from
home today.



Some Other Challenges

Challenges at Advanced Nodes

Increasing Rules Increases Complexity and Runtime



- **Multi-day runtimes due to increasing rules, complexity**
 - Large N3 SoC runtime > 24 hrs with 1000 cores
- **Debug is complex and time-consuming**
 - Require guidance to find root cause of DRC, LVS and Antenna issues
- **Extensive hardware compute requirements**

Why IC Validator



Scalability to 4000 Cores

Overnight Runtimes



40% Compute Savings

Elastic CPU: Optimized use of compute
Cloud: PPU license model for peak demand



Explorer DRC & LVS

Isolate key design weaknesses within hours



2X Faster Debug Convergence

Find root cause of issues quickly to accelerate TAT



Fusion

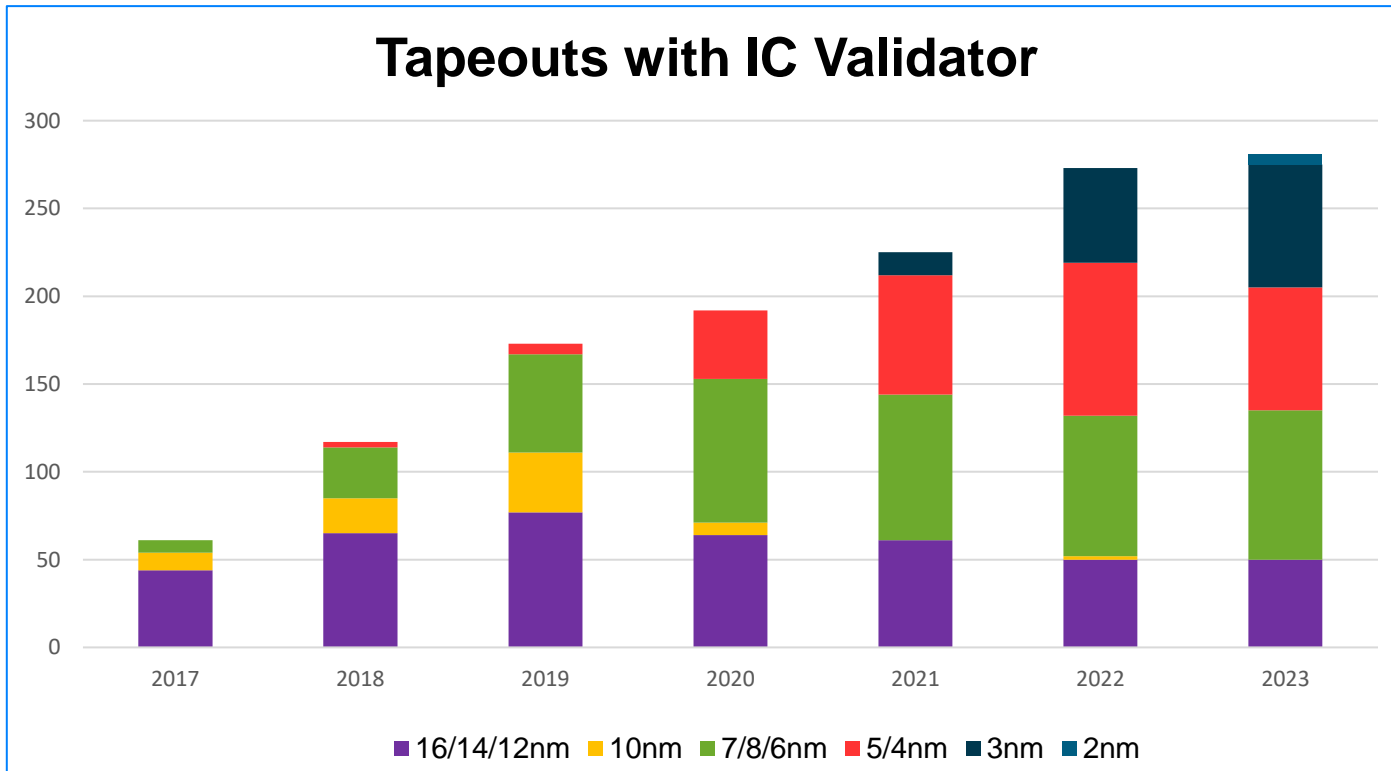
Signoff DRC/Fill, Live DRC and PGA in FC and StarRC early-start flow

2X Faster with 1/2 Resources

IC Validator Signoff Momentum



Tapeouts Across Broad Range Of Designs / IPs, Foundries & Process Nodes



Source: TSMC OIP, DDTS, SNUG Presentations, Webinar

6+ 2nm
Testchip

100+ 3nm
Tapeouts/Testchips

80+ 5nm
Tapeouts/Testchips

60+ 12nm
Tapeouts/Testchips

Strong Foundry Collaboration

Golden Signoff Certified at TSMC, Samsung, IFS and GF



TSMC

Process	DRC	LVS	Fill
N2	✓	✓	✓
N3	✓	✓	✓
N4	✓	✓	✓
N5	✓	✓	✓
N6	✓	✓	✓
N10	✓	✓	✓
N12	✓	✓	✓
N16	✓	✓	✓
N20	✓	✓	✓
N22	✓	✓	✓
N28	✓	✓	✓
N45/N40	✓	✓	✓
N65/55	✓	✓	✓

Natively developed and Same day runset release for N5 & newer

Samsung Foundry

Process	DRC	LVS	Fill
14A	●	●	●
2nm	●	●	●
3nm	●	●	●
4nm	●	●	●
5nm	●	●	●
7nm	●	●	●
8nm	●	●	●
10nm	●	●	●
11nm	●	●	●
14nm	●	●	●
18nm	●	●	●
28nm	●	●	●

Multiple 3nm or newer projects signoff using IC Validator

Global Foundries

IC Validator Signoff Status for GF 12nm and 22nm PDKs

Runset	Status
DRC	Qualified
LVS	**Qualified
FILL	Qualified
MAS	Qualified
DRC+	Qualified

** LVS is not required for signoff.

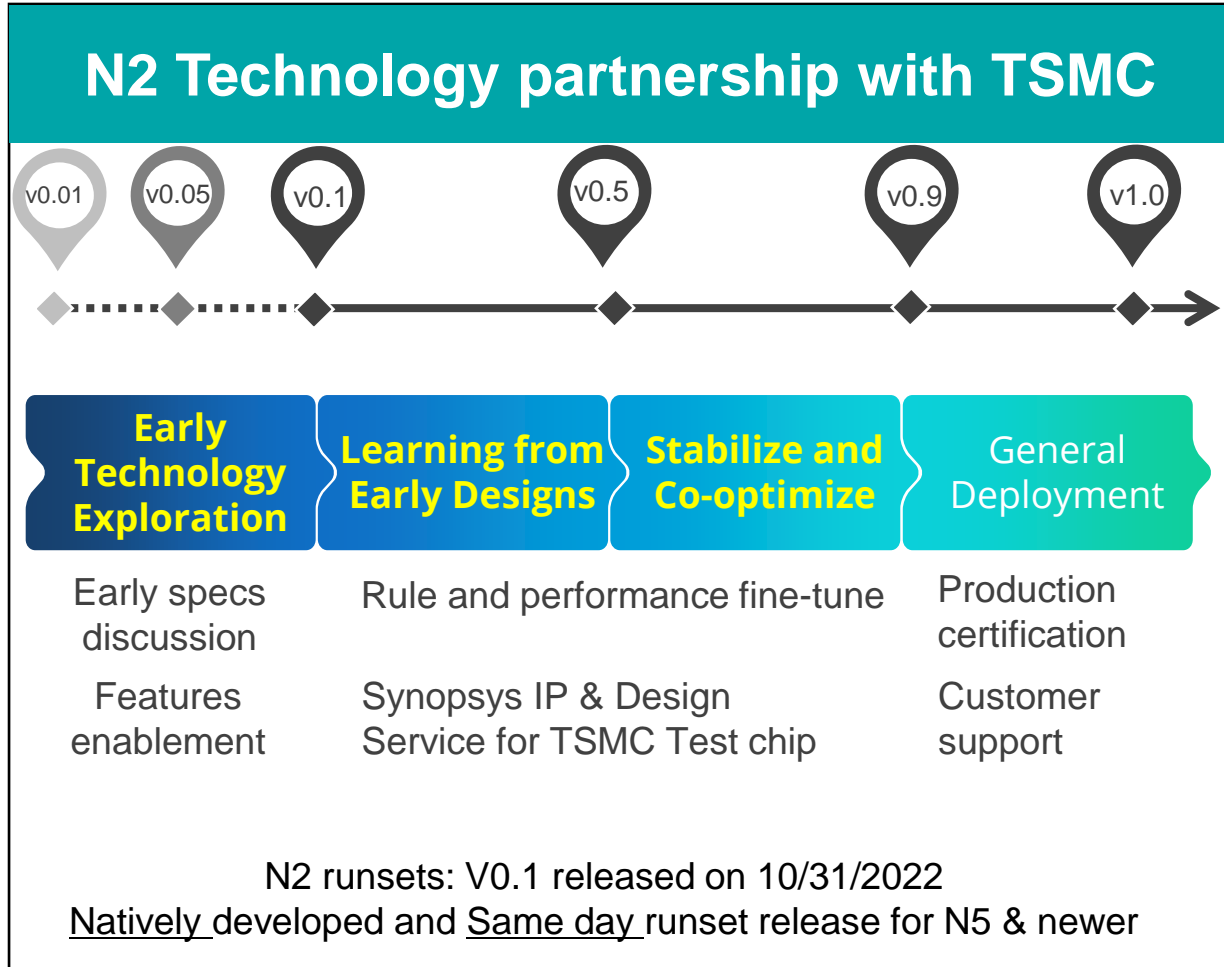


GLOBALFOUNDRIES Confidential 1

Signoff certified for 12nm, 14nm and 22nm processes




100% Intel process projects signoff with IC Validator

TSMC Collaboration Beyond Enablement



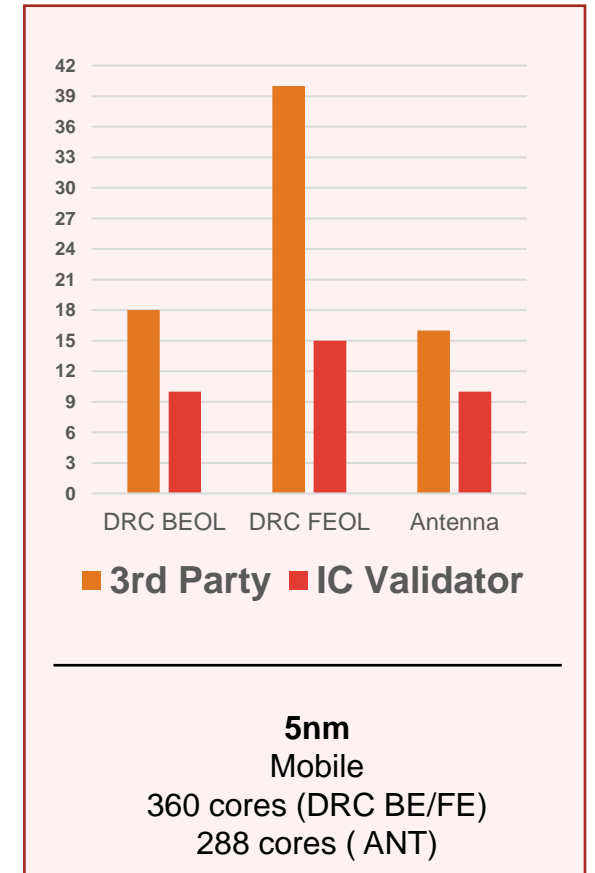
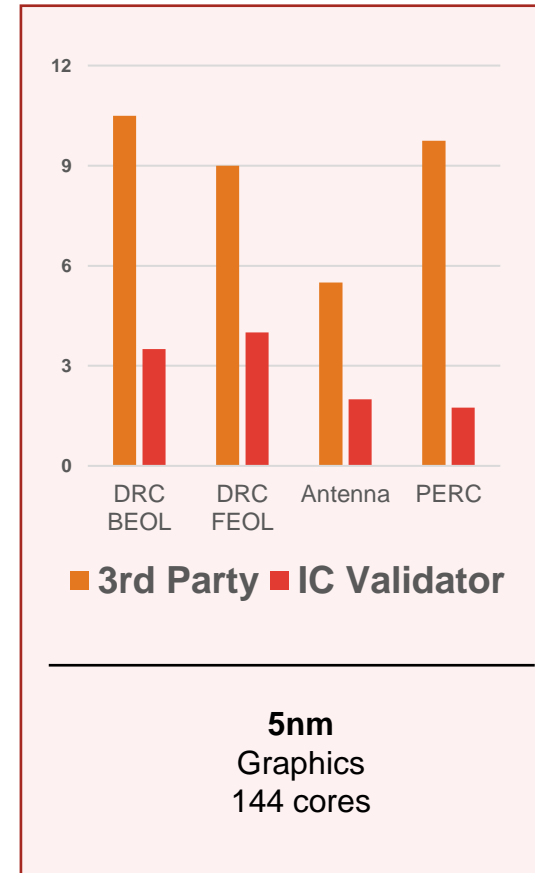
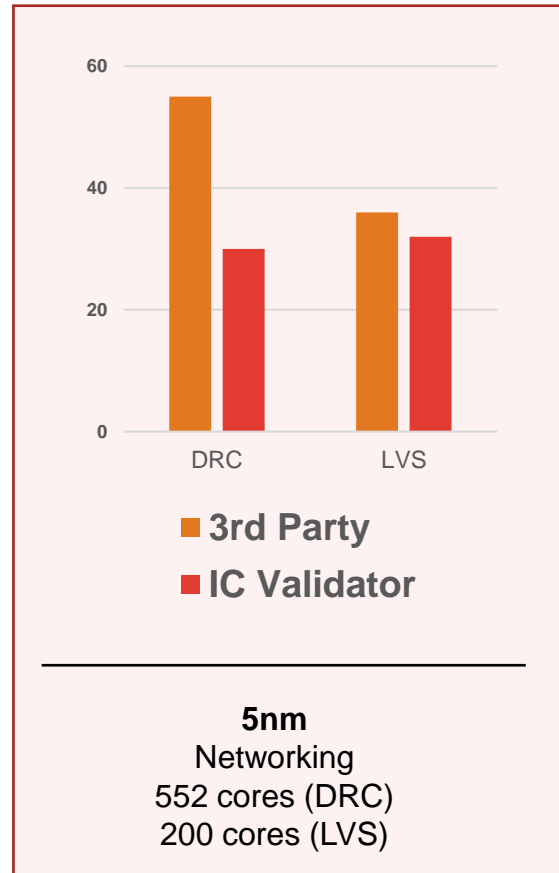
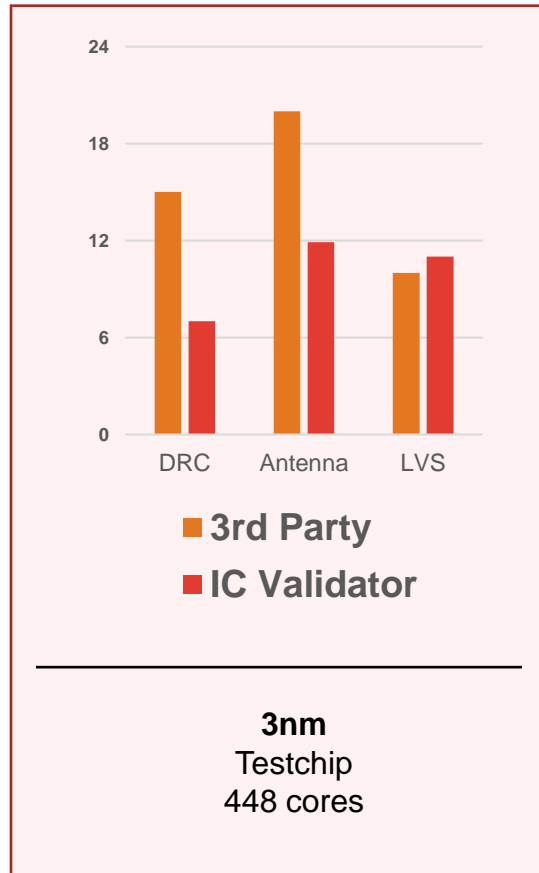
- ## Tool of choice for TSMC IP team
- **Primary** DRC / LVS Signoff at DTP
 - Foundry tapeouts for pathfinding and IP silicon validation
 - **TSMC tapeouts** – **6** at N2 and **24** at N3
 - **100+** tapeouts at N3 across all customers

Key Signoff ICV Wins

Resource Optimization	Accelerate Design Closure	1.5X Faster LVS
<p>Hardware Cost</p>  <p>Intel CPU 3nm, 5nm Elastic automatically optimizes allocation of machine resources</p> <p>40% Compute Savings</p>	<p>Dirty Design Verification</p>  <p>Cerebras AI 5nm, 7nm Explorer enables rapid iterations to accelerate dirty design verification</p> <p>4X Faster DRC/LVS</p>	<p>Performance</p>  <p>Aster Labs High Speed Connectivity IP 5nm, 7nm Scalability enables LVS to be 1.5X faster than competition</p> <p>200 Core LVS Scalability</p>

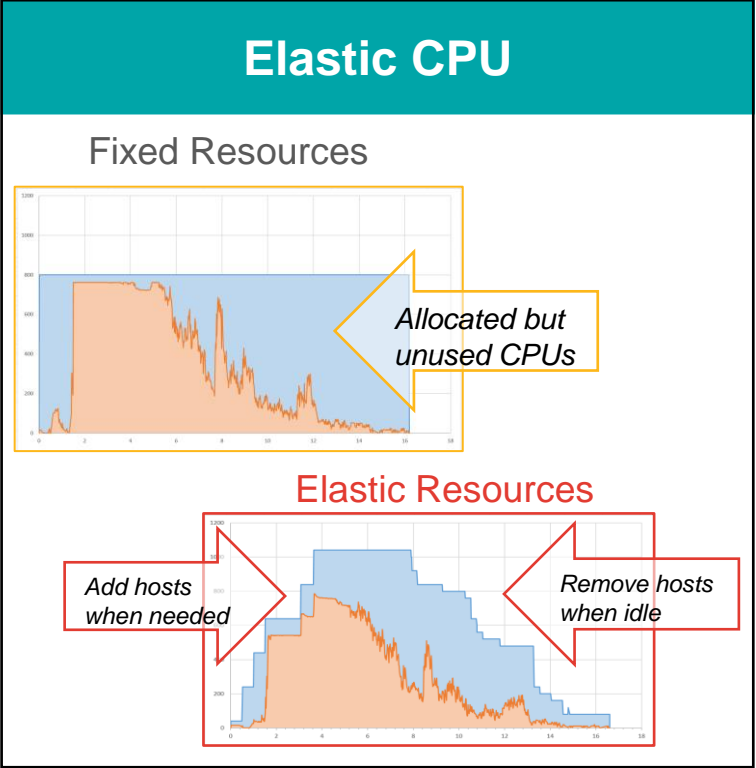
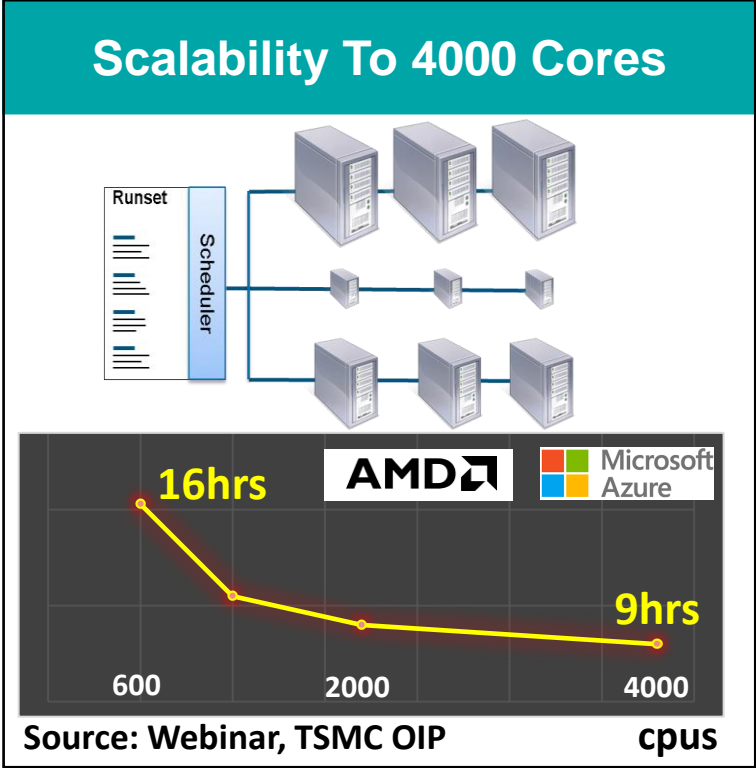
Performance Leadership at Advanced Nodes

Recent Benchmark data



1.5X faster on DRC, PERC and ANT

Scalability Technology Leadership



Cloud Optimized

SYNOPSYS Cloud

Microsoft Azure

Portal | Pay-Per-Use Analytics | Security

TSMC SAMSUNG

TSMC Cloud Alliance
Samsung SAFE

2X Speed-Up

Massive Parallel Processing
Memory aware
Smart Scheduler

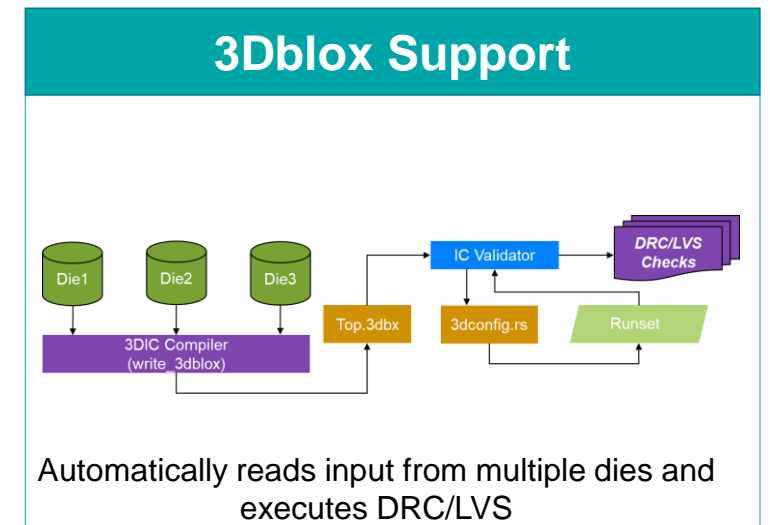
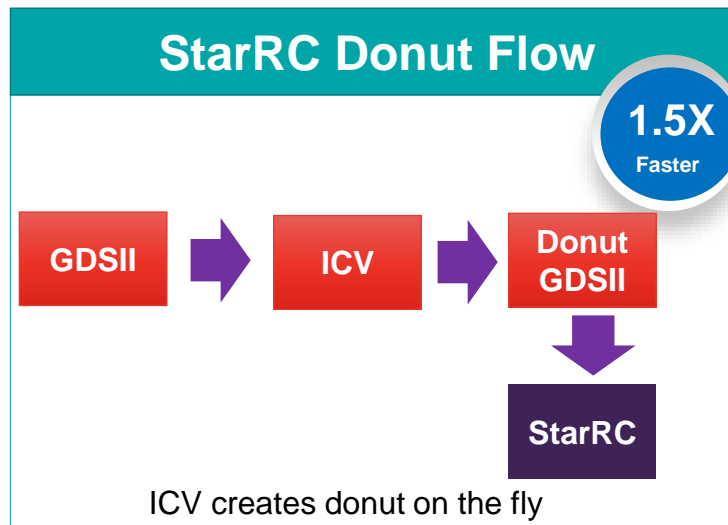
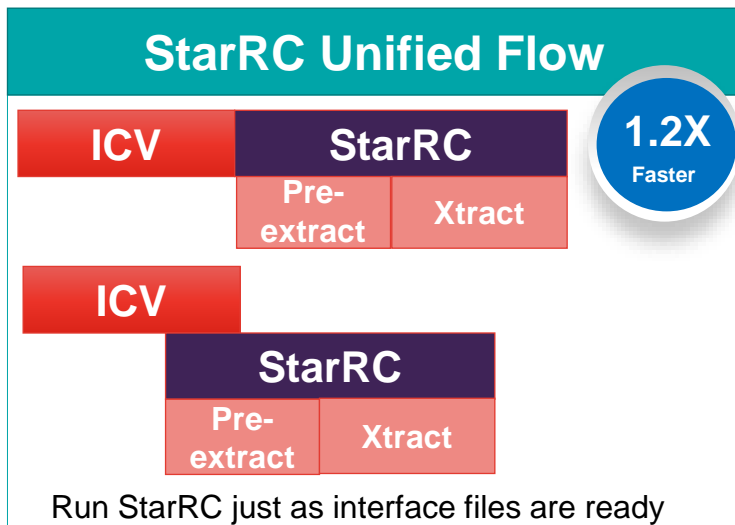
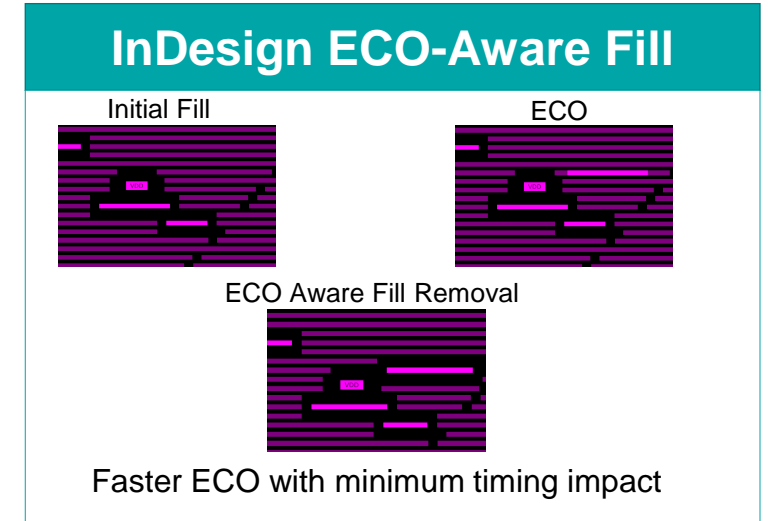
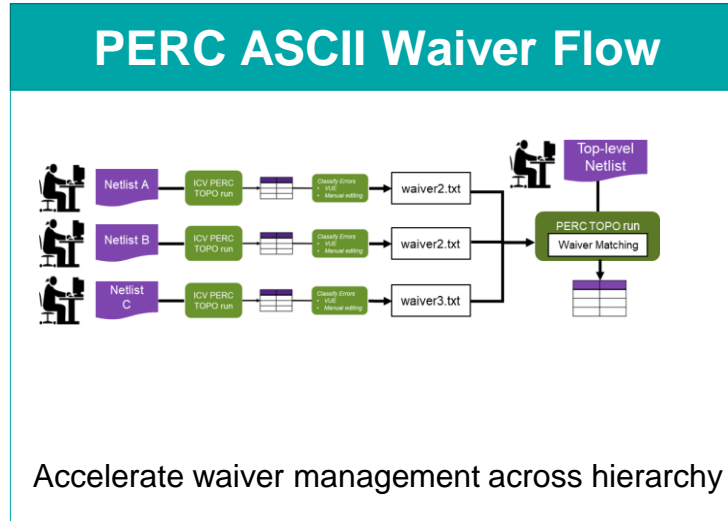
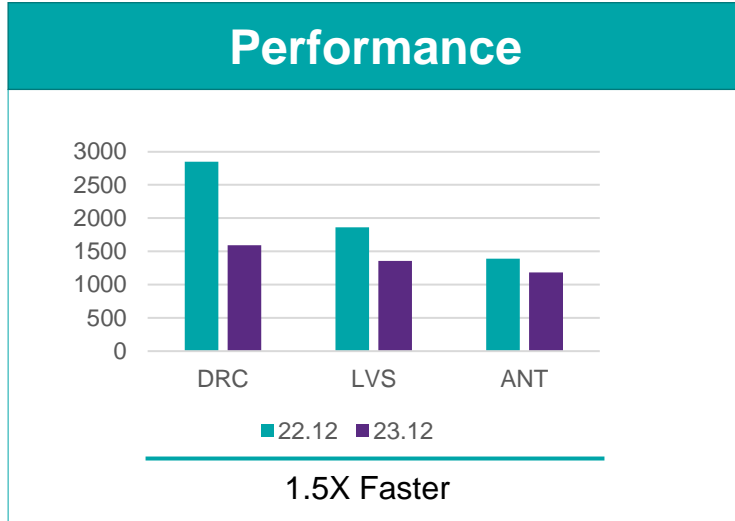
40% Compute Savings

Eliminate queue time
Lower peak license usage

40% TTR Improvement

Immediate on-demand use for peak

IC Validator 2023.12 Release Highlights



Faster Design Convergence with Fusion and StarRC



Timing Aware Signoff Fill

Automated Remove and Refill

Balance timing and density requirements

Power Grid Augmentation

Route_opt NDM database

ICC II

- Redhawk In-Design Analysis-1
- PGA
- Redhawk In-Design Analysis-2
- ICV In-Design Metal Fill

Chip Finish NDM database

Improve Voltage Drop

Automatic DRC Fixing (ADR)

Accelerate closure with nominal impact to timing

Ultra Fast ECO

DRC and Fill ECO within minutes

Live DRC

DRC feedback within seconds

FC / IC Compiler II

shapes ↓ ↑ errors

IC Validator Live

StarRC Donut Flow

I/P GDSII → ICV → Donut GDSII

Use ICV to create donut on the fly and send to StarRC

StarRC

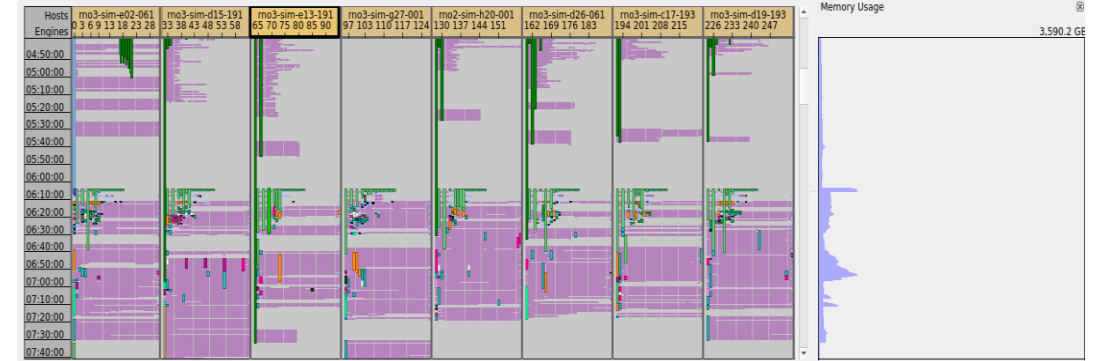
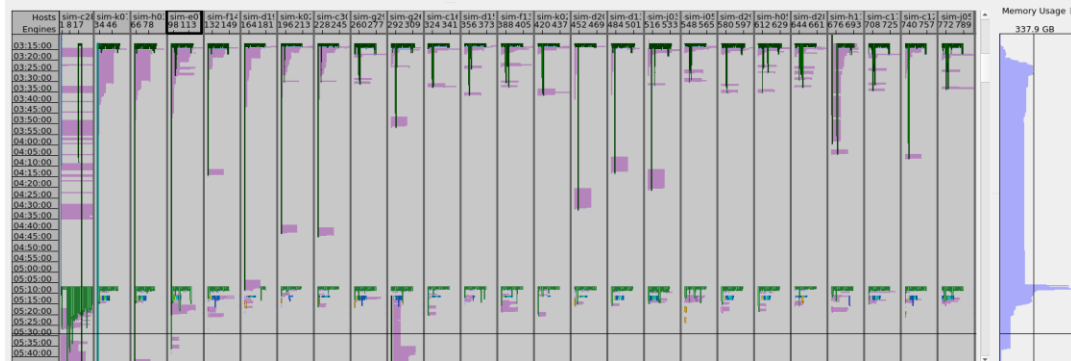
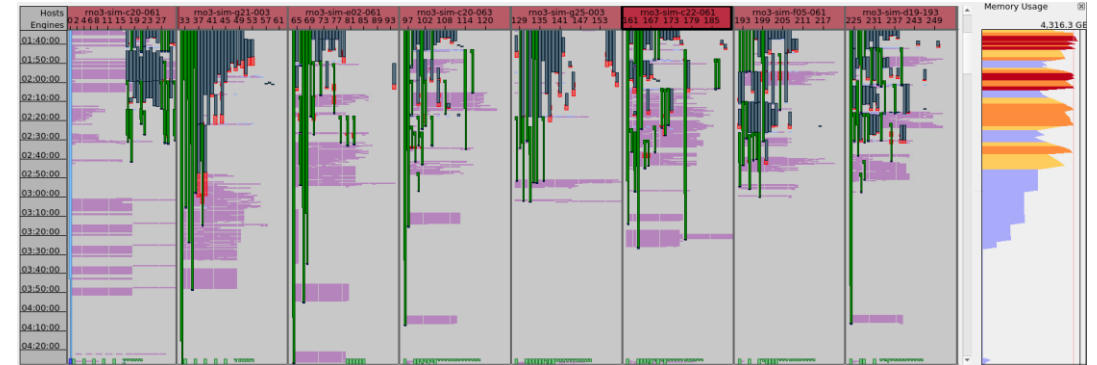
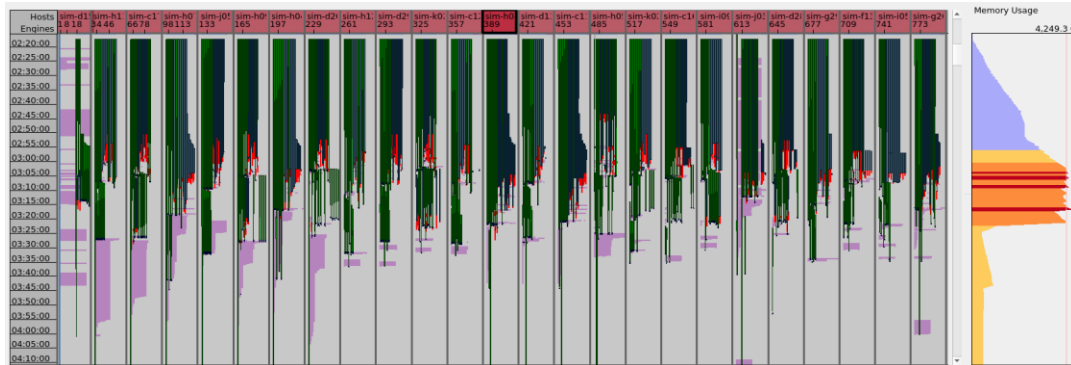
1.5X Faster TAT

Customer Case Study: Peak Memory on N5 Design



DRC Default Peak Memory: 4T
After Improvements: 337G

Antenna Default Peak Memory: 4T
After Improvements: 200G

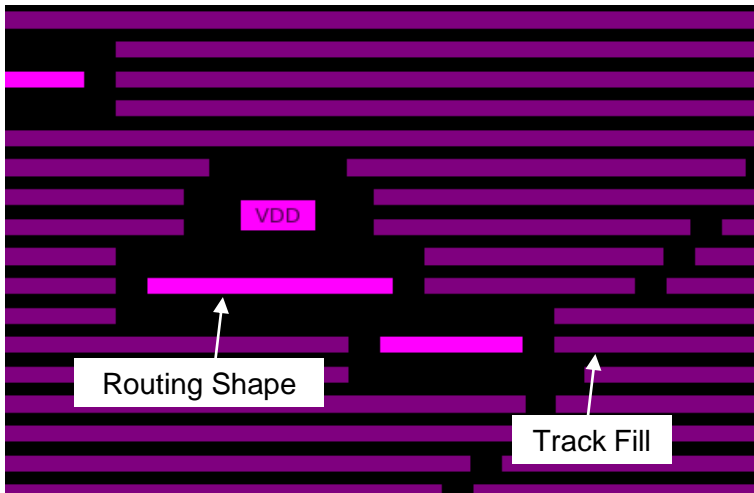


10X DRC and 20X Antenna Peak Memory Reduction

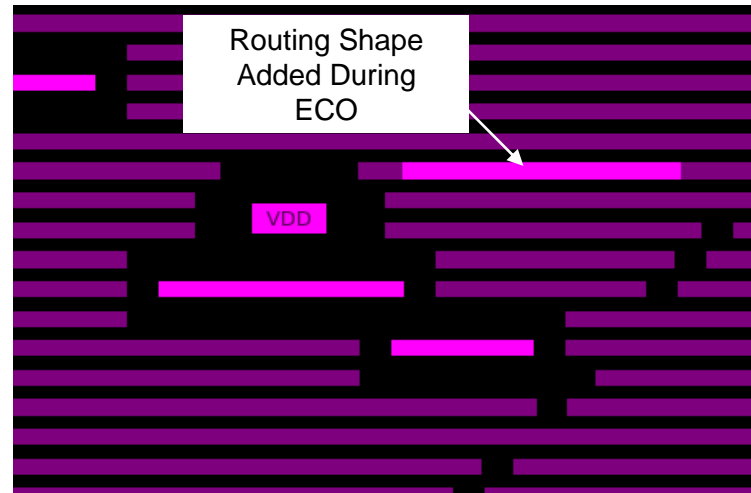
InDesign ECO-Aware Fill Removal For DRC Clean Results

- Automatic track fill removal in ECO areas
 - Applicable to normal track fill and power grid augmentation (PGA) flows
- No need to generate DRC error markers with `signoff_check_drc`, `check_routes`, or `check_pg_drc`

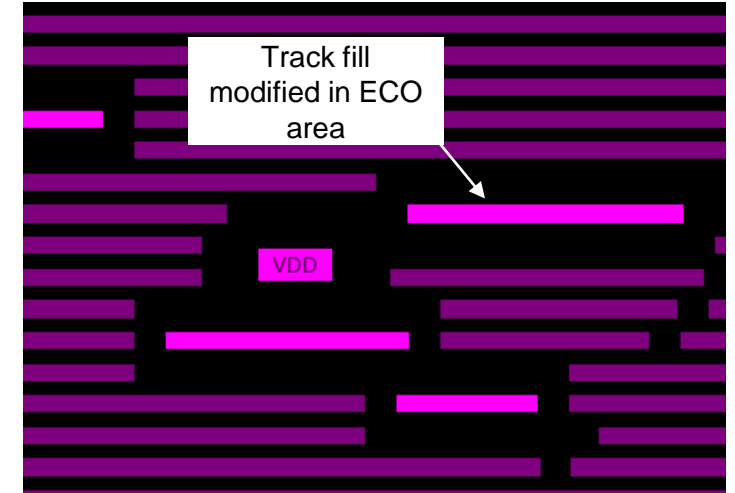
Design After Initial Track Fill Insertion



ECO Change



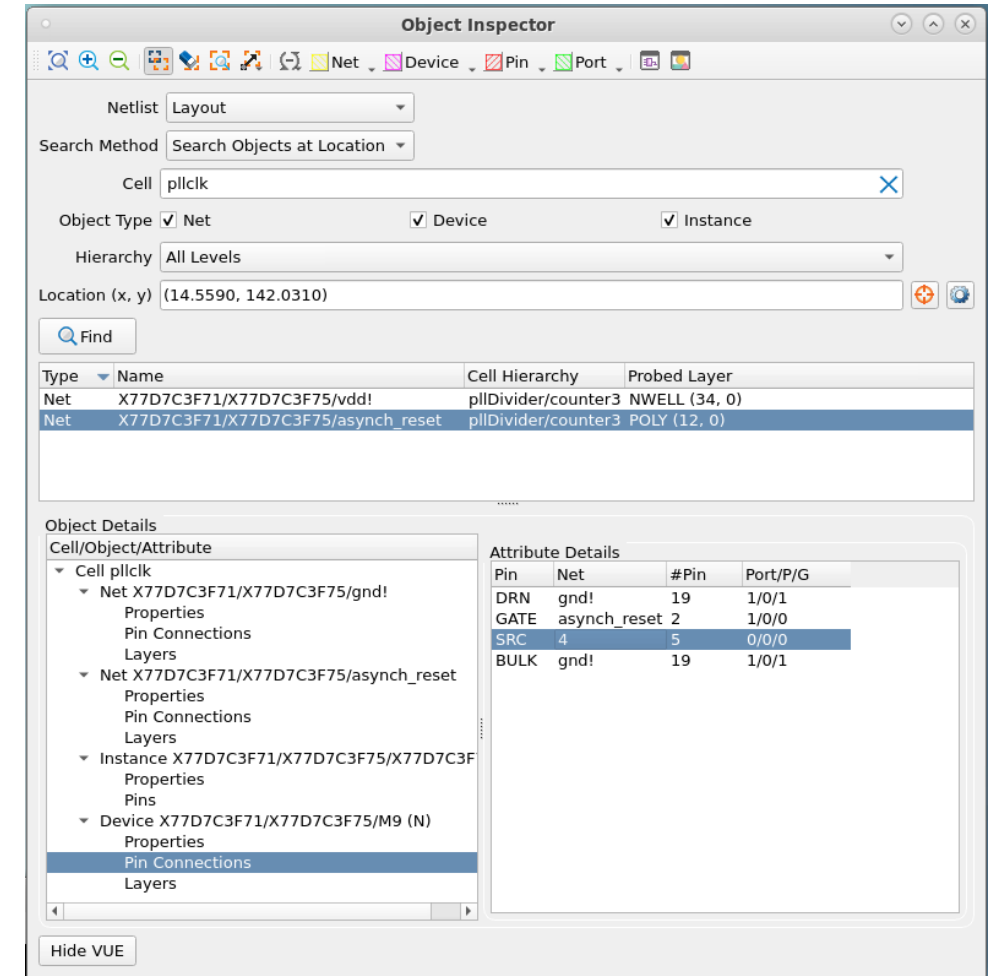
Design After ECO Aware Fill Removal



LVS VUE Object Inspector



- Direct Access to extracted netlist data for debugging LVS ERC or complex LVS errors
- Probe the layout to get a list of netlist objects located at that point
- Find detailed information about items like pin connections, properties, or layers
- Flexible highlight controls
- Trace Paths through devices

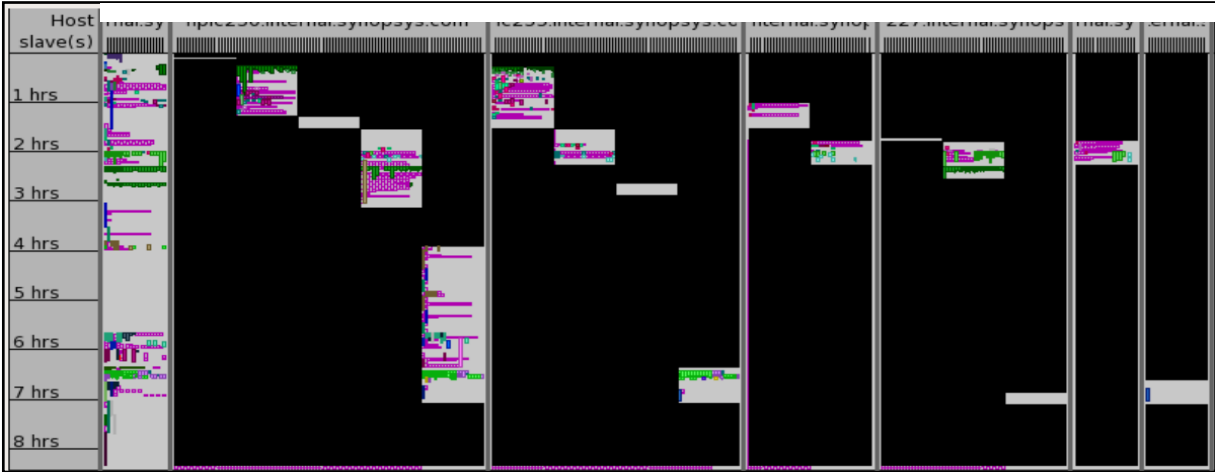
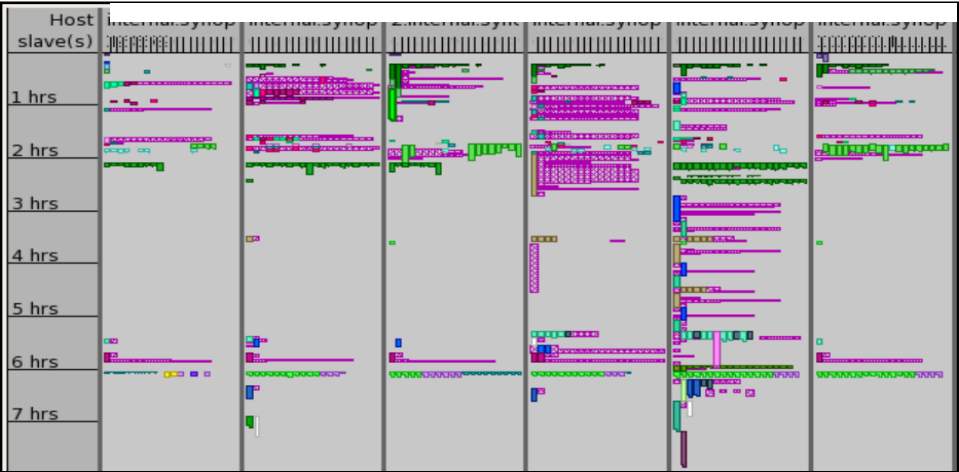
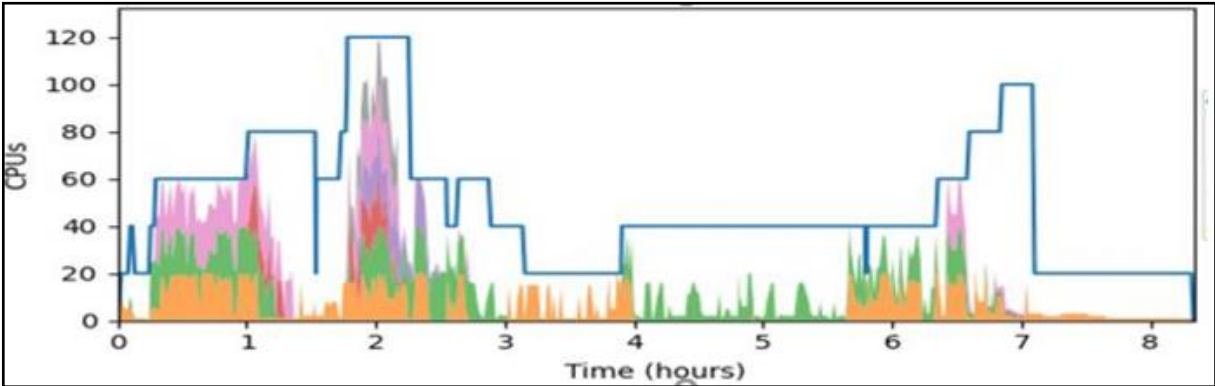
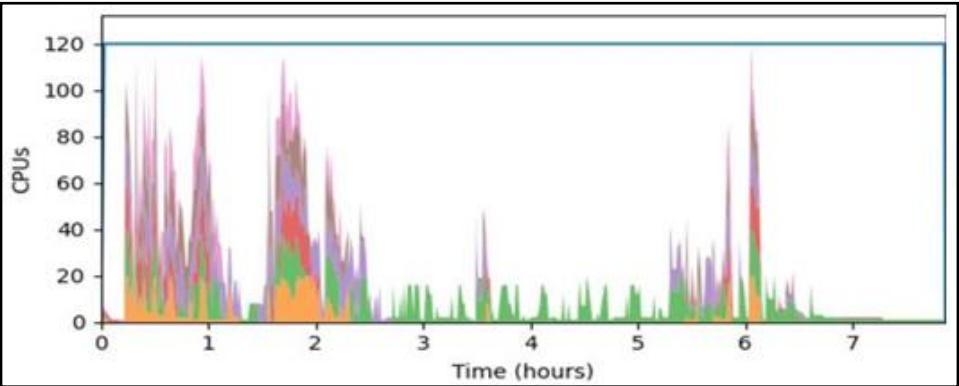


Customer Case Study: Elastic CPU for LVS on N5 Design



Normal run: Wall time 7:50Hours
Allocated CPU Hours: 943.7

Elastic run: Wall time 8:20Hours
Allocated CPU Hours: 410

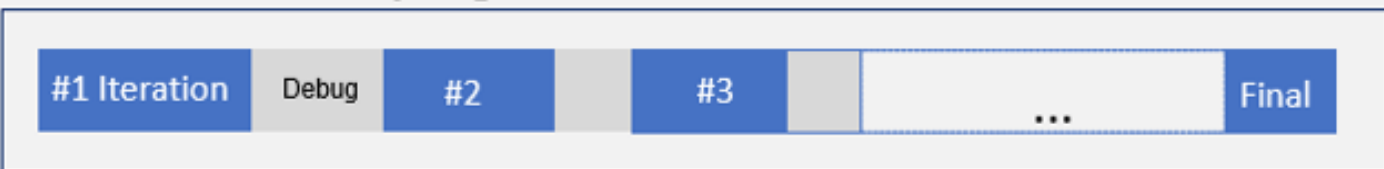


50% resource and license savings with 5% overhead in wall time

Customer Case Study: 7nm 650 mm² design

Rapid verify → fix turns during chip integration

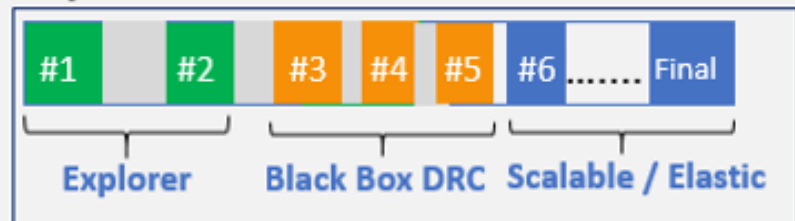
Traditional Full Chip Signoff



DRC: 27 hrs

LVS: 19 hrs

Explorer + BB DRC + ML Driven Root Cause Analysis



DRC Explorer: 6.5 hrs

LVS Explorer: 5.0 hrs



LVS Explorer – 4X Faster

- Shorts/Opens at Top and all design hierarchy
- Connectivity mismatches

DRC Explorer – 4X Faster

- Fill/Block/Via overlaps
- Pin Location Mismatches

Black Box DRC – Decrease Noise

- Filter known macro errors

Root Cause Analysis



- Identify structural design issues

Scalable / Elastic

- Improve compute / license efficiency

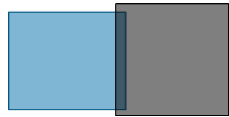
Explorer DRC Identifies Key Design Issues Within Hours



Hours vs Days
Innovative technology for dirty design verification

Issues During Integration

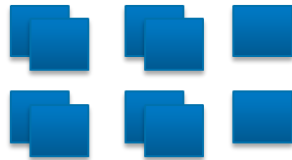
Block Overlap



Fill Overlap



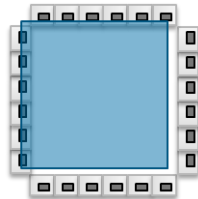
Via Overlap



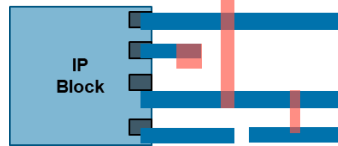
Missing Blockages



Pad Ring Overlap



Pin Location Mismatch



Long runtimes,

Billions of errors – tough to debug root cause

Explorer DRC

5X

Faster

Runtime

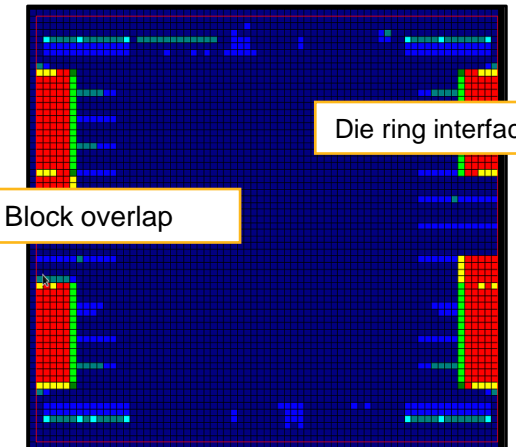
5X

Fewer

CPUs

Identify key issues within hours

DRC Heat Map



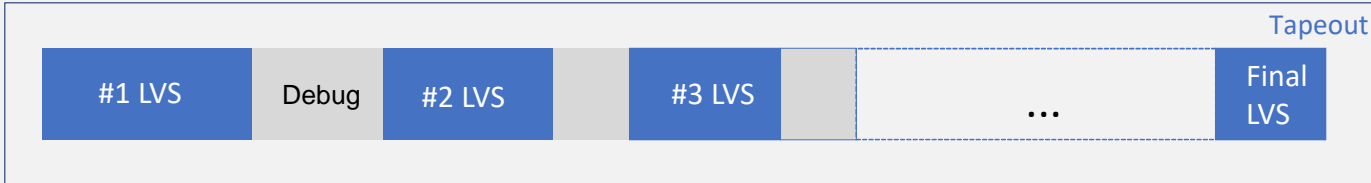
Immediately isolates clusters of errors

Explorer LVS: 2X Faster LVS Signoff Cycle

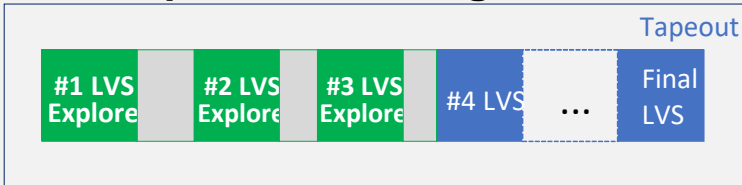


Able to do rapid verify → fix turns

Traditional Full Chip LVS Signoff



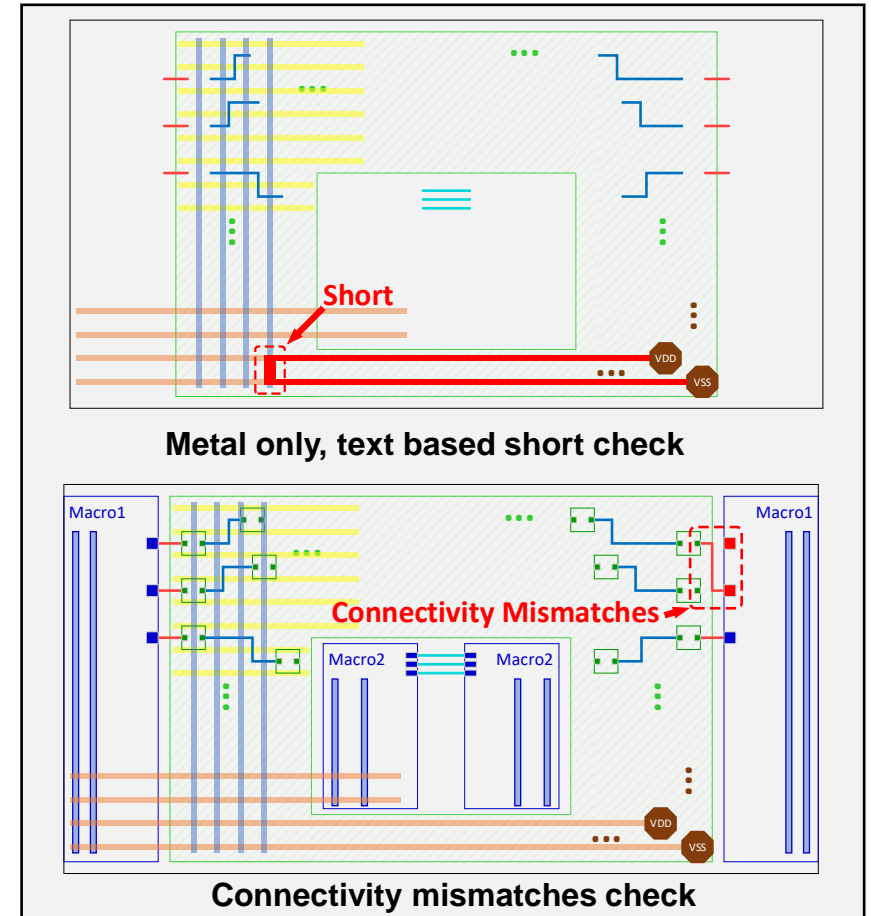
LVS Explorer + LVS Signoff



Upto 2X faster PV Cycle

Quickly find – Up to 10x Faster

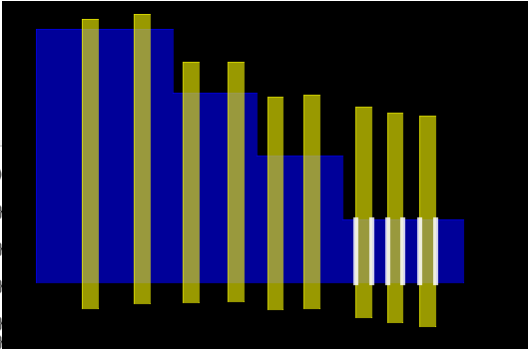
- Shorts at Top
- Shorts/Opens in all design hierarchy
- Connectivity mismatches in all design hierarchy



Unparalleled Innovations to Accelerate Debug



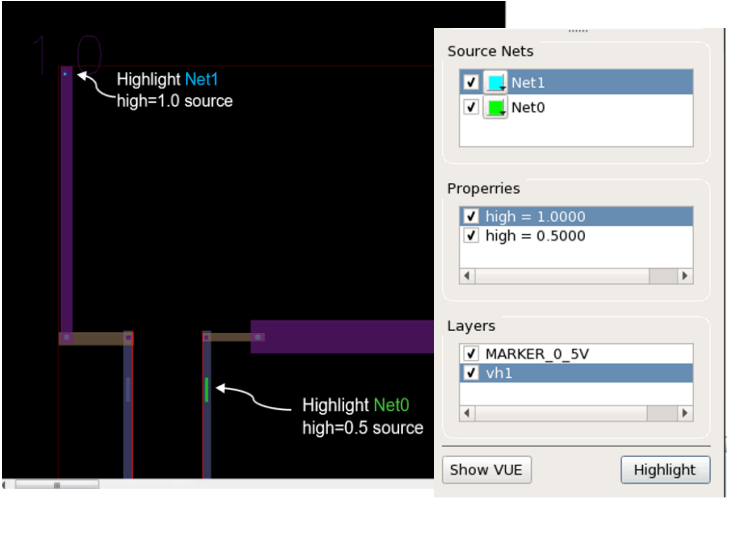
Layer Debugger



```
Nwell = assign({ { 2 } }  
Tox = assign({ { 3 } } )  
Poly = assign({ { 13 } } )  
Met1 = assign({ { 16 } } )  
Via1 = assign({ { 17 } } )  
Met2 = assign({ { 18 } } )  
Via2 = assign({ { 27 } } )  
Met3 = assign({ { 28 } } )  
Via3 = assign({ { 29 } } )  
Met4 = assign({ { 31 } } )  
Met6 = assign({ { 38 } } )  
gate_G1 = length_edge(gate_layer, <= 1.5)  
external2(gate_G1, Poly, < 0.15, NONE, look_t ru = COINCIDENT)  
comment = "R.Poly.G1: Min Space Poly to Gate for Gate Width <=1.5 must be >= 0.15"
```

Highlight intermediate layers out-of-the box to debug complex rules

Delta-Voltage



Highlight Net1
high=1.0 source

Highlight Net0
high=0.5 source

Source Nets
 Net1
 Net0

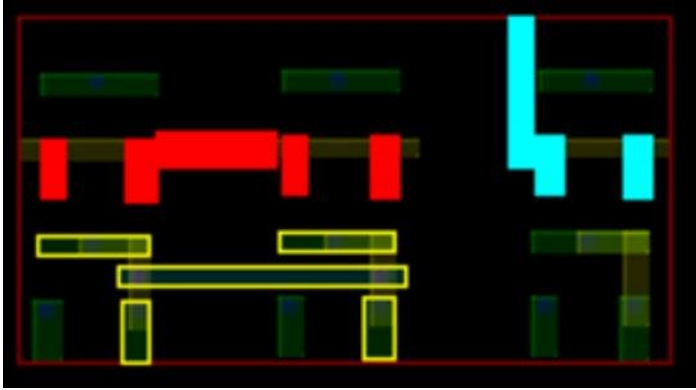
Properties
 high = 1.0000
 high = 0.5000

Layers
 MARKER_0_5V
 vh1

Show VUE Highlight

Highlight entire net with voltage sources for faster debug

Antenna Debug



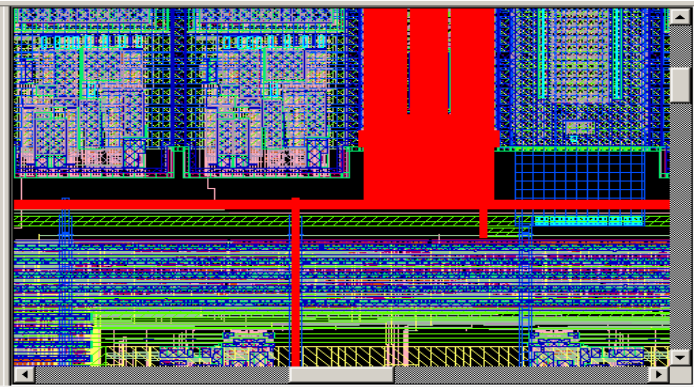
Highlight multiple nets for easier debug

2X Faster PV Convergence

Unparalleled Innovations to Accelerate Debug

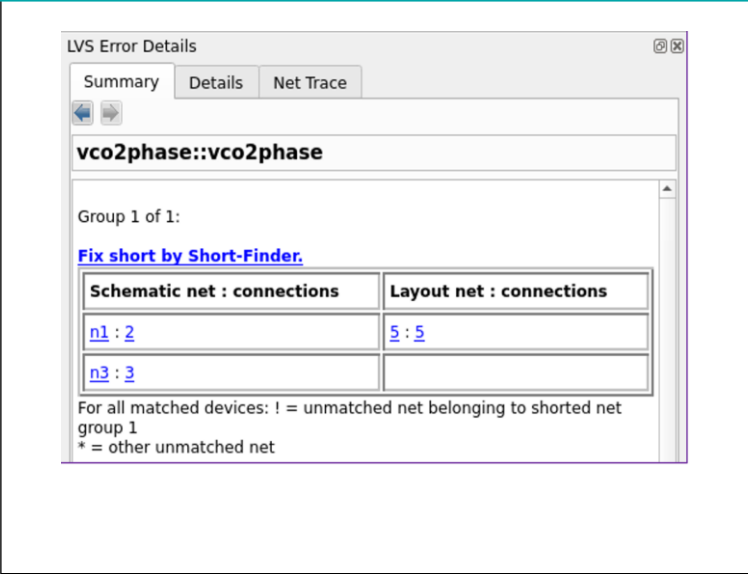


LVS Short Finder Interactive Short Analysis



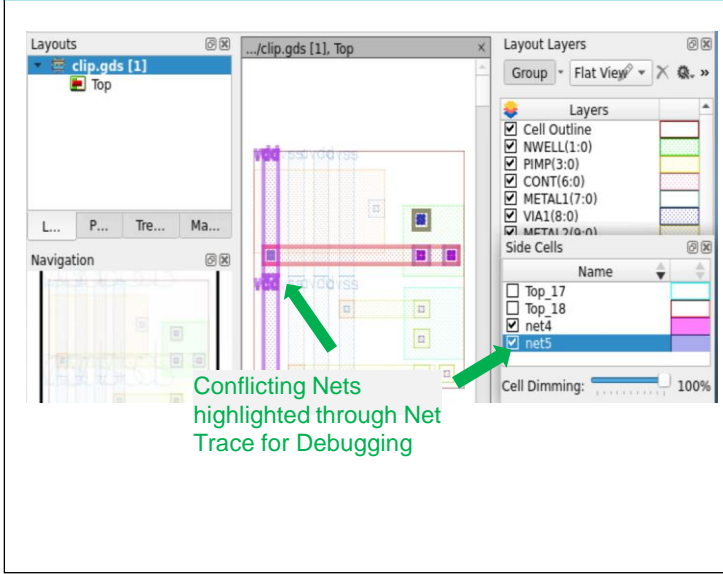
Multiple text-shorts debug without rerunning LVS

LVS-Aware Short Finder



Fix logical shorts using interactive short finder

LVS Soft Check



Show conflicting metal nets attached to well islands

2X Faster PV Convergence

Machine Learning Solution

ML-Enhanced Physical Verification

Accelerate Verification

Faster performance

Scheduler
Fast runtime

Hierarchy Optimization
Efficient DRC, LVS data processing

Leap in Productivity

Reduce Physical Verification TAT

Heatmap Clusters
Fast convergence

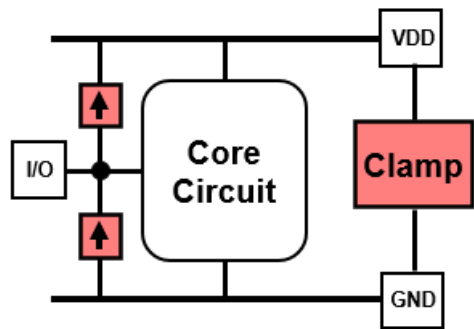
Automatic Root-cause identification
Fast convergence

End-to-End ESD Solution

Technologies from Schematic to Layout



ICV PERC - TOPO



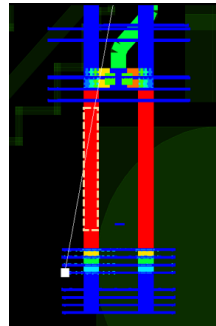
Fully programmable netlist analysis

Recognize and report full ESD network

Foundry Certified

Python programming language

ICV PERC – CD/P2P



Unmatched full chip performance, 94B Tx

Star-RC golden Extraction

Foundry Certified

Silicon Proven on SNPS IP

PrimeESD - HBM



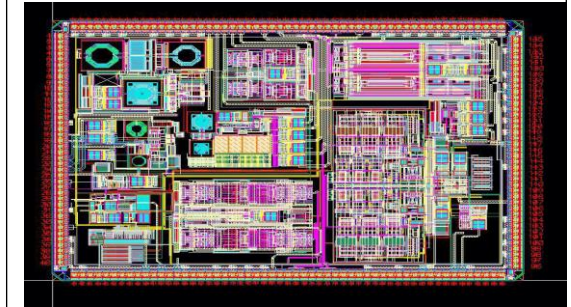
Full chip HBM Analysis

Finds core device and interconnect failures

Highlights cause of failures

Identifies unused or lightly used ESD Devices

PrimeESD - CDM



Full chip CDM Analysis

Supports ESD Device snapback

Charge distribution algorithm supports all design styles

Supports inductance and capacitance

Enabling Designers to Achieve ESD Proof Designs

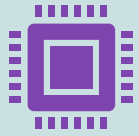
Customer Successes



CDM Issue - Transient Effects	CDM Issue - Package Effects	HBM Issue - Device Stress Checks
<p data-bbox="244 525 639 575">Inductance Issue</p> <div data-bbox="112 618 782 982"><p data-bbox="137 636 417 668">European Customer</p><p data-bbox="529 636 761 686">RF Design</p><p data-bbox="137 739 206 765">16nm</p><p data-bbox="129 829 754 968">PrimeESD CDM uncovered failure due to Inductance missed by other tools</p></div> <p data-bbox="244 1033 639 1150">Improved Design Reliability</p>	<p data-bbox="899 539 1472 589">Charge Distribution Issue</p> <div data-bbox="868 618 1538 982"><p data-bbox="899 629 1039 661">Major IDM</p><p data-bbox="1276 622 1531 715">Touch Screen Design</p><p data-bbox="899 739 968 765">28nm</p><p data-bbox="912 822 1523 961">PrimeESD CDM uncovered failure due to charge distribution caused by package</p></div> <p data-bbox="983 1048 1391 1165">Improved System Reliability</p>	<p data-bbox="1803 532 2275 582">Core Device Failures</p> <div data-bbox="1709 618 2379 982"><p data-bbox="1722 629 1905 661">US Customer</p><p data-bbox="2232 625 2359 718">AMS Design</p><p data-bbox="1722 739 1791 765">40nm</p><p data-bbox="1747 822 2359 961">PrimeESD HBM uncovered failure In core devices missed by other tools</p></div> <p data-bbox="1837 1025 2244 1142">Improved Design Reliability</p>

Summary

TSMC Golden Certified, Natively Developed Runsets, 100+ N3 Tapeouts



Scalability to 4000 cores



40% compute savings



2X faster debug convergence

How to get through in Ho Chi Minh Traffic





Smart Traffic là việc sử dụng công nghệ và thông tin để cải thiện hiệu suất và giải quyết các vấn đề về giao thông. Sử dụng các công nghệ tiên tiến như cảm biến, hệ thống thông tin liên lạc, trí tuệ nhân tạo và phân tích dữ liệu để thu thập, xử lý và chia sẻ thông tin về giao thông.





Extreme heat during Ho Chi Minh Summer



Tận hưởng mùa hè thật phong cách



THANK YOU

Our
Technology,
Your
Innovation™